

<b>Notice of References Cited</b>	Application/Control No. 10/777,506		Applicant(s)/Patent Under Reexamination BAUDAT, NED	
	Examiner Richard L. Leung		Art Unit 3744	Page 1 of 1

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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